

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination PETERSON ET AL.	
		Examiner Kathleen S. Yuan	Art Unit 2624	Page 1 of 1

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*	B	US-5,046,109	09-1991	Fujimori et al.	382/144
*	C	US-4,578,810	03-1986	MacFarlane et al.	382/147
*	D	US-5,444,480	08-1995	Sumita, Masahiko	348/127
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**NON-PATENT DOCUMENTS**

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	U	Allan et al, Critical Area Extraction for Soft Fault Estimation, Febuaury 1998, IEEE, Vol II, No 1, pg. 1-3
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

• Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.